

Search Notes

Application/Control No.

09/634,339

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under
Reexamination

KAYE, EVAN JOHN

Art Unit

2176

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|------------------------------|-----------|----------|
| 715 | 501.1 500.1 514 526 | 10/4/2006 | MK |
| 709 | 200 202 203 | 10/4/2006 | MK |
| 707 | 6 102 | 10/4/2006 | MK |
| 84 | 609 649 668 | 10/4/2006 | MK |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| Inventor Name Search | 10/3/2006 | MK |
| NPL (ACM) | 10/3/2006 | MK |
| West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout | 10/4/2006 | MK |
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